#### Status of the Beam Phase and Intensity Monitor for LHCb

TFC Team: Richard Jacobsson Zbigniew Guzik <u>Federico Alessio</u>

Motivation Aims Overview of the board Debugging Performance Future plans



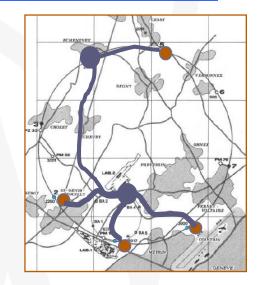
## Why BPIM?

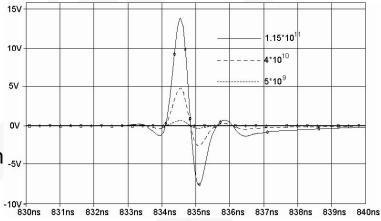
General clock issues:

- Clock locked with the beam transmitted over 14 km of optical fibres at a depth of ~1 m
- Estimated diurnal (200 ps) and seasonal drift (7 ns) due to temperature variations (AB/RF ref.)
- Aid in the coarse and fine time alignment of the experiment
- Monitor individual bunch position (ghost bunches)
- Measure bunch intensity bunch-by-bunch for trigger conditions
- Measure bunch phase bunch-by-bunch for long-term stability in clock distribution

Able to

- See single bunch crossing: signal coming from BPTXs for LHCb, very fast and high bipolar pulse.
- Check trigger/detector timing alignment real-time and tag events with bunch information through the TFC system (Interfaced with ODIN)





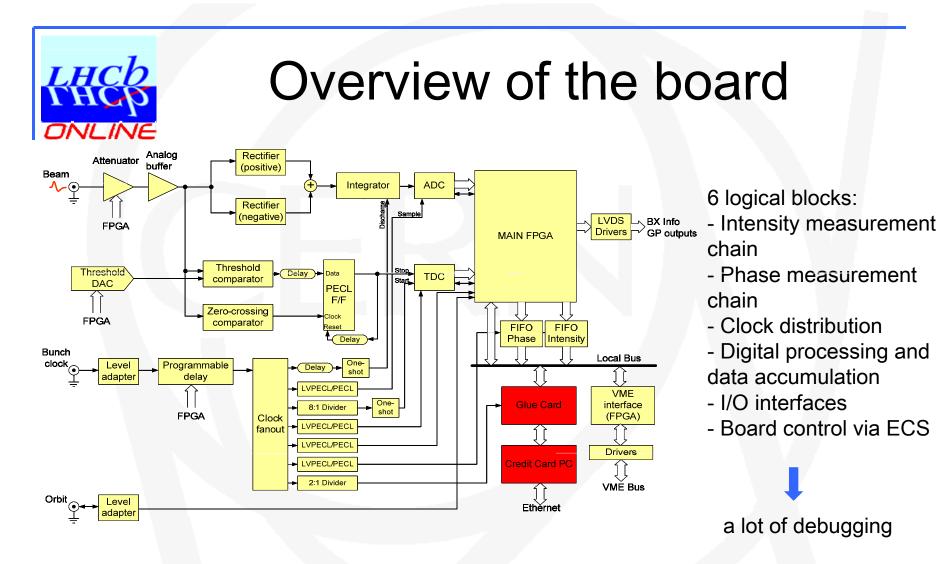


#### What do we aim to?

- Developing custom made acquisition board:
  - 6U VME, one per beam
  - Online analysis of a bipolar pulse: FWHM 1 ns at 40 MHz, ±5Vmax processing amplitude (onboard attenuator for higher pulses)
  - Measure time between bunch arrivals and LHC bunch clock locally
    - Bunch-by-bunch for a full LHC turn filled in FIFO
    - Triggered via controls interface
    - <100 ps precision and averaging phase as a function of bunch crossing
  - Measure continuously bunch intensities bunch-by-bunch
    - 12-bit resolution by integrating pulse per bunch
    - Output intensity on front-panel at 40 MHz (8/4-bit resolution)
    - Triggered via controls interface, fill in FIFO with intensities for full turn
    - Intensity per bunch as a function of bunch crossing
  - Readout and control via Experiment Control System, CCPC based interface and VME alternatively
  - Interfaced directly to LHCb Timing and Fast Control system
  - Data processing on FPGA



Picture of the 1<sup>st</sup> prototype



Every block has been tested and adjusted, and all blocks are working!

41st LEADE meeting



# Debugging

The first prototype has been mounted and debugged in stages: a lot of modifications (thanks to the Mounting Workshop!) and understanding of the problems.

➤ The analog chain is designed with current-feedback amplifiers: impressive slew rate and high gain-bandwith.

> The stabilization of the rectifier chains has been a difficult task: the current feedback amplifiers are very unstable, but the best configuration has been found

New designs of the integrator have been implemented: improve stability, undershoot and baseline

Programmable attenuator fixed and constant-level-crossing method with programmable level (DAC)

Fixed Start and Stop signals for the TDC, still a problem with one mode of operation to be investigated with the manufactury (ACAM)

> A lot of PECL – LVPECL and LVPECL – TTL translators implemented for improvements

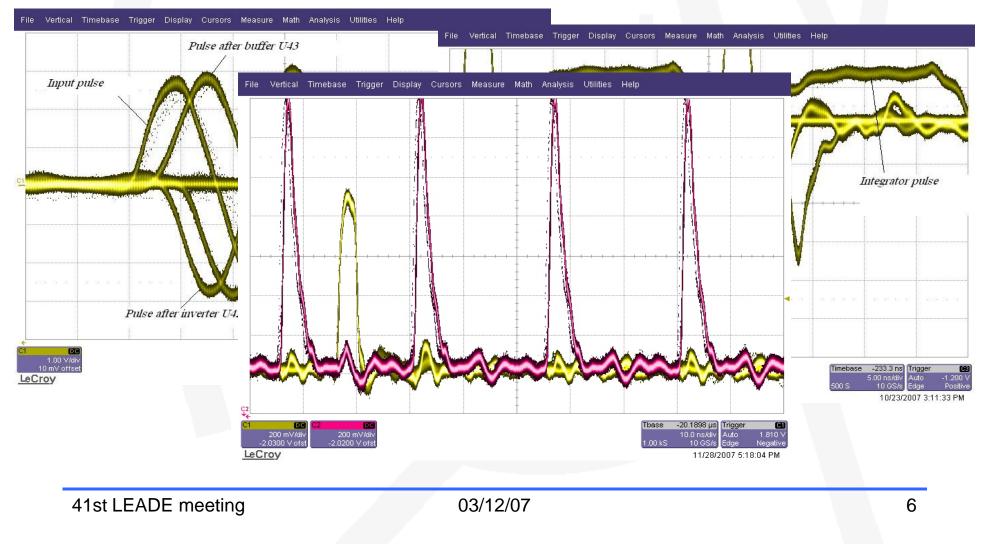
- > Firmware written and implemented to control FIFOs for Intensity and Phase measurement
- > FIFOs are autonomous: each FIFO has its own RCLK, WCLK, OE, RENB, WENB

The board has very satisfactory performance!



### Analog processing

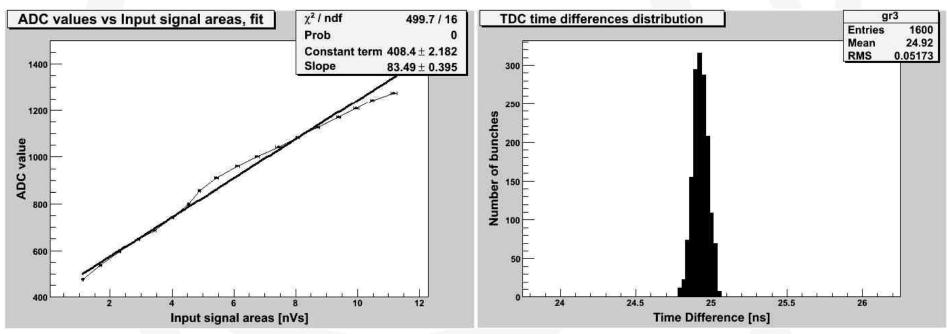
The analog chain for the intensity measurement is working as simulated





### Performance in the lab

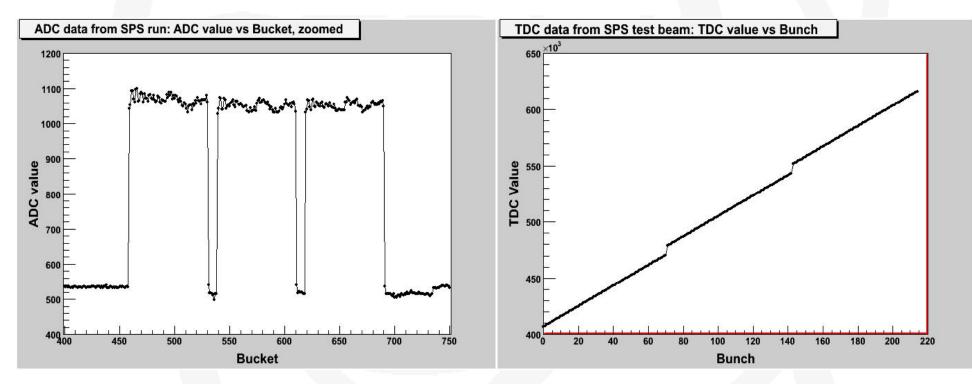
The board has extensively been tested in laboratory ...



- Linearization to be performed in the FPGA during the data processing
- > Understanding of the TDC problem in order to improve the confidence on the distribution

# Performance in the SPS

... and in the SPS with a LHC-like structure 72 bunches (in 3 groups) spaced by 25 ns.



Undershoot of the baseline after the sampling of the bunches to be understood



### Conclusions

 $\succ$  A second prototype has been designed with the mentioned changes. The production of 2 boards will be launched in the next weeks.

> We are confident that the second prototype will work as designed.

> The boards will be tested in the lab during January/February.

Unless major problems come up, the test process should be short and the production will be extended to a few more boards depending on the interest of other experiments.

Thank you for your attention.